FORM PTO 1449 (*modified*)	ATTY DOCKET NO.	APPLICATION NO.
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	**NL031031US1**	**10/570,290**
	APPLICANT **Adrianus Josephus Bink, et al.**	
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)	FILING DATE **February 28, 2008**	GROUP **2185**

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,666,482	**9/9/1997**	**McClure**			
		5,958,068	**9/28/1999**	**Arimilli, et al.**			
		2001/0039601	**11/8/2001**	**Leung et al.**			
		6,393,504	**5/21/2002**	**Leung et al.**			
		6,467,048	**10/15/2002**	**Olarig et al.**			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

		Yamashita, K. et al. "A Design and Yield Evaluation Technique for Wafer-Scale Memory", Computer, vol. 25, issue 4, pgs. 19-27 (4/1992)
		Otterstedt, et al. "Test and Reconfiguration Experiments for a Defect-Tolerant Large Area Monolithic Multiprocessor System", Proc. of Int. Conf. on Wafer Scale Integration, San Franciso, pp. 315-23 (1/1994)
		Lu, et al. "Fault-Tolerant Interleaved Memory Systems With Two-Level Redundancy", IEEE Trans. on Computers, vol. 46, no. 9 (9/1997)
		Shirvani, et al. "PADded Cache: A New Fault-Tolerance Technique for Cache Memories", Proc. 17th IEEE VLSI Test Symposium (1999)
		Chakraborty, K. et al. "A Physical Design Tool for Build-In Self-Repairable Static Rams", Proc. of the Conf. on Design, Automation, and Test in Europe, Munich, DE (1999)
		Low, "An Efficient Reconfiguration Algorithm for Degradable VLSI/WSI Arrays", IEEE Trans. on Computers, vol. 49, no. 6, pgs. 553-59 (6/2000)
		Baik, et al. "Re-evaluation and Comparison of Fault Tolerant Cache Schemes", Univ. of Wisconsi Madison ECE Dept. 753 Course Project (2002)
		International Preliminary Report on Patentability for Int'l. Patent Appln. No. PCT/IB2004/51465 (March 6, 2006)

EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.